



SLOVENSKI STANDARD
SIST ISO 3274:2001/TC1:2001
01-julij-2001

GdYWZ_UYU[Yca Yf]g_l j Y]]b]nXY_U!`HY_gli fUdcj fy]bY.`dfcZ]bUa YrcXU!
-a Ybg_YnbU]bcgh]_cbfU_fb]]bglfi a Ybhcj !`HY b] b]`dcdfUj Y_`%

Geometrical Product Specifications (GPS) — Surface texture:Profile method — Nominal characteristics of contact (stylus) instruments

iteh STANDARD PREVIEW
(standards.iteh.ai)

Ta slovenski standard je istoveten z: **ISO 3274:1996/Cor 1:1998**
<https://standards.iteh.ai/catalog/standards/sist/b63a71f4-4e4c-400c-97a2-1724fb6eded0/sist-iso-3274-2001-tc1-2001>

ICS:

17.040.30 Merila Measuring instruments

SIST ISO 3274:2001/TC1:2001 en

iTeh STANDARD PREVIEW
(standards.iteh.ai)

[SIST ISO 3274:2001/TC1:2001](https://standards.iteh.ai/catalog/standards/sist/b65a71f4-4e4c-400c-97a2-1724fb6eded0/sist-iso-3274-2001-tc1-2001)

<https://standards.iteh.ai/catalog/standards/sist/b65a71f4-4e4c-400c-97a2-1724fb6eded0/sist-iso-3274-2001-tc1-2001>



INTERNATIONAL STANDARD ISO 3274:1996
TECHNICAL CORRIGENDUM 1

Published 1998-06-01

INTERNATIONAL ORGANIZATION FOR STANDARDIZATION • МЕЖДУНАРОДНАЯ ОРГАНИЗАЦИЯ ПО СТАНДАРТИЗАЦИИ • ORGANISATION INTERNATIONALE DE NORMALISATION

**Geometrical Product Specifications (GPS) — Surface texture:
Profile method — Nominal characteristics of contact (stylus)
instruments**

TECHNICAL CORRIGENDUM 1

Spécification géométrique des produits (GPS) — État de surface: Méthode du profil — Caractéristiques nominales des appareils à contact (palpeur)

RECTIFICATIF TECHNIQUE 1

iTeh STANDARD PREVIEW
(standards.iteh.ai)

Technical Corrigendum 1 to International Standard ISO 3274:1996 was prepared by Technical Committee ISO/TC 213, *Dimensional and geometrical product specifications and verification*.

<https://standards.iteh.ai/catalog/standards/sist/b65a71f4-4e4c-400c-97a2-1724fb6eded0/sist-iso-3274-2001-tc1-2001>

Page 1

Clause 2

Replace “ISO 4287:1996” with “ISO 4287:1997”.

Page 12

Figure C.1

Replace “Datum planes” with “Datums”.

ICS 17.040.30

Ref. No. ISO 3274:1996/Cor.1:1998(E)

Descriptors: surface condition, roughness, surface waviness, measuring instruments, profile meters, characteristics.

ISO 1998

Printed in Switzerland